

#4
S.Y
07-16-03

3502-1006

PATENTS



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of

Juha KARUNEN et al.

Confirmation No. 9556

Serial No. 10/067,826

Group 2878

Filed February 8, 2002

METHOD AND ARRANGEMENT FOR PROCESSING MEASUREMENT DATA

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

162800 MAIL ROOM

JUL - 8 2003

RECEIVED

Sir:

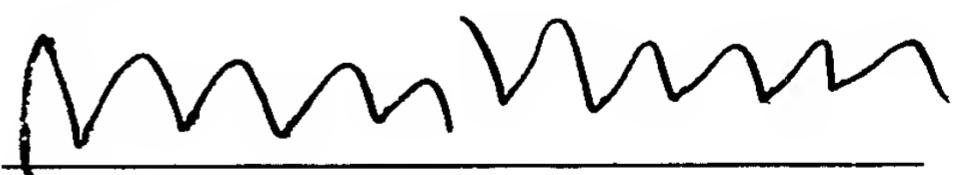
In compliance with Rules 1.97 and 1.98, and in fulfillment of the duty of disclosure under Rule 1.56, the accompanying documents, copies of which are attached to this statement, are made of record on the enclosed sheet.

A concise explanation of the relevance of these items is that these references were cited by the European Patent Office in the corresponding European Application Serial No. 03 39 6013. A copy of the European Search Report in which they were cited is attached hereto.

Respectfully submitted,

YOUNG & THOMPSON

By

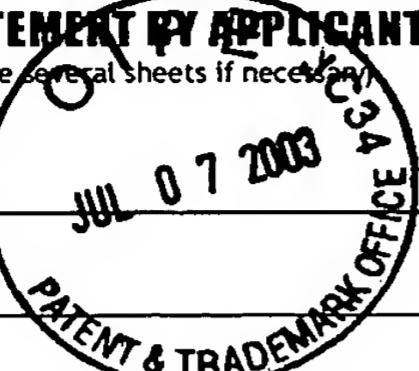

Robert J. Patch
Attorney for Applicant
Registration No. 17,355
745 South 23rd Street
Arlington, VA 22202
Telephone: 703/521-2297

July 7, 2003

FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
3502-1006SERIAL NO.
10/067,826INFORMATION DISCLOSURE
STATEMENT BY APPLICANT

(Use several sheets if necessary)

37 CFR 1.98(b)

APPLICANT
Juha KARUNEN et al.FILING DATE 00
February 8, 2002GROUP
2878

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	PATENT NUMBER	ISSUE DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
AA						
AB						
AC						
AD						

FOREIGN PATENT OR PUBLISHED FOREIGN PATENT APPLICATION

	DOCUMENT NO.	PUBL. DATE	COUNTRY OR PATENT OFFICE	CLASS	SUB CLASS	TRANSLATION YES NO
AI	2002-185724	06/02	JP			English abstract
AJ	2001 177756	06/01	JP			English abstract
AK	0 776 124 A2	05/97	EP			
AL						
AM						
AN						
AO						
AP						
AQ						

RECEIVED
JUL -8 2003
TC 2800 MAIL ROOM

OTHER DOCUMENTS (Including Author, Title, Date, Relevant Pages, Place of Publication)

AT	
AU	
AV	
AX	
AY	

EXAMINER

DATE CONSIDERED

EXAMINER: Initial citation considered. Draw line through citation if not in conformance and not considered.
Include copy of this form with next communication to applicant.